

Figure 1

TI-35524

1

identifying parameters and making list

measuring first parameter on FAB A device (1-n)

calculating P_{1A} & P_{99A} .

measuring first parameter on FAB B devices (1-m)
and calculating P_{1B} & P_{99B} .

combining FAB A & FAB B data, determining
 $P_1 = \max[P_{1A}, P_{1B}]$ & $P_{99} = \min[P_{99A}, P_{99B}]$.

determining $X_{(k-1)} < P_1 \leq X_{(k)}$; $(p) \leq P_{99} < X_{(p+1)}$ and calculating $S_{AB} = ((p-k+1) / (m+n)) / 98\%$.

If $98\% \leq S_{AB}$, FAB A and FAB B are equal wrt first parameter.

repeating steps 102 – 108 on other parameters on list

If all S_{AB} 's are greater or equal to 98%, FAB A and FAB B are equal.

Figure 2

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2

identifying parameters and making list

measuring first parameter on FAB A baseline device (1-n)

recording data 1 to n.

calculating P_1 & P_{99} . from data 1 to n.

measuring first parameter on FAB B devices (1-m) and recording data.

using FAB B data, determining $X_{(k-1)} < P_1 \leq X_{(k)}$; $X_{(p)} \leq P_{99} < X_{(p+1)}$ and calculating $S_{AB} = ((p-k+1) / m) / 98\%$.

calculating $S_{AB} = ((p-k+1) / m) / 98\%$.

If $98\% \leq S_{AB}$, FAB B devices conform to baseline wrt first parameter.

repeating steps 102 – 108 on other parameters on list

If all S_{AB} 's are greater or equal to 98%, FAB B devices conform to baseline.

Figure 3

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3

identifying parameters and making list

measuring first parameter on FAB A device (1-n)

recording FAB A data (1-n)

arranging FAB A data in arrayA.

Inserting pre-determined limits C and D
into array and determining $X_{(k-1)} < C \leq X_{(k)}$; $(p) \leq D$
 $< X_{(p+1)}$

calculating $CD S_A = ((p-k+1) / (n)) / 98\%$.

If $98\% \leq CD S_A$, FAB A devices conform to pre-determined limit wrt first parameter.

repeating steps 302 – 308 on other parameters on list

If all $CD S_A$'s are greater or equal to 98%, FAB A devices conform to pre-determined limit in total